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Tailoring the A.C. Electrical Properties of $\text{TiO}_2/\text{Si}_3\text{N}_4$ -NPs-Doped PVP to Use in Electrical and Electronics Applications

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This work aims to investigate the A.C. electrical properties of PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites (PVP—polyvinyl pyrrolidone) to employ them in various electrical and electronic applications. The A.C. electrical properties of PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites are measured in frequency range from 100 Hz to 5 MHz. The results show that the dielectric parameters such as dielectric constant, dielectric loss and electrical conductivity are increasing with an increase in $\text{TiO}_2/\text{Si}_3\text{N}_4$ concentration. The dielectric constant and dielectric loss of PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites are reduced, while the electrical conductivity is increased, with increasing of the frequency. The obtained results indicate that the PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites can be useful in different electrical and electronics fields.

Цю роботу спрямовано на дослідження електричних властивостей нанокompозитів ПВП/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ (ПВП — полівінілпіролідін) на змінному струмі для використання їх у різних електричних та електронних застосуваннях. Електричні властивості на змінному струмі у нанокompозитах ПВП/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ міряються в діапазоні частот від 100 Гц до 5 МГц. Результати показують, що діелектричні параметри, такі як діелектрична проникність, діелектричні втрати й електропровідність, зростають зі збільшенням концентрації $\text{TiO}_2/\text{Si}_3\text{N}_4$. З підвищенням частоти діелектрична проникність і діелектричні втрати нанокompозитів ПВП/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ зменшуються, а електропровідність збільшується. Одержані результати вказують на те, що нанокompозити ПВП/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ можуть бути корисними в різних сферах електрики й електроніки.

Key words: nanocomposite, $\text{TiO}_2/\text{Si}_3\text{N}_4$, polymer, dielectric constant, conductivity.

Ключові слова: нанокompозит, $\text{TiO}_2/\text{Si}_3\text{N}_4$, полімер, діелектрична проникність, електропровідність.

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1. INTRODUCTION

Modern electronics heighten the demand for adaptable, multipurpose, eco-friendly dielectric materials with superior properties. Historically, ceramics were used as dielectric materials; however, it possessed undesirable properties such as brittleness, processing difficulties, and low stability. Polymers have superior flexibility, processability, and lightweight, when compared to ceramics. In addition, they gained significant interest in science and technology during the last decade as a dielectric or interfacial layer between metals and semiconductors. Among the polymers, biodegradable, non-toxic, and hydrophilic ones have specific research interest, as they can be applicable in bioelectronics [1].

Flexible electronics are attracting increased attention in the electronic industry day by day due to their compact nature and ease of handling. Along with other electronics, flexible dielectric materials are also getting popular for many applications like in field effect transistors (FET), gate dielectrics, pulse power systems, sensors and energy storage devices, *etc.* Polymers are attractive to synthesize flexible materials, but they have limitations of low capacitance and low dielectric constants. In last few years, efforts have been made to enhance dielectric constant of polymers using by either dielectric or conducting fillers [2].

Silicon nitride (Si_3N_4) is a non-oxide ceramic material with a density of 3.4 g/cc, with high thermal conductivity 30 W/(m·K), low thermal expansion, and high compressive strength 4500 MPa. In addition, it has high-temperature stability, high fracture toughness, and high thermal shock resistance [3].

Nanocrystalline TiO_2 is a humongous semiconductor with many useful features, such as excellent photocatalytic activity and chemical and thermal stability. It is a low-cost and non-toxic semiconductor with unique properties, which allow insertion of it as nanoparticles (NPs) into polymeric matrices, and this is potential strategy for developing new nanocomposites with improved properties [4].

PVP is an amorphous and water-soluble polar polymer due to the existence of double bond in pyrrolidine ring, and hydroxyl groups existing in the structure [5].

The nanocomposites have nanostructure doped with various materials and are included in many applications in various approaches like radiation shielding and bioenvironmental [6–11], energy storage [12–14], electronics and optoelectronics [15–29], optical fields [30–39], sensors [40, 41], antibacterial [42–47].

The present work objects to investigate the dielectric properties of PVP/TiO₂/Si₃N₄ nanocomposites to employ in various electrical and electronics applications.

2. MATERIALS AND METHODS

Films of PVP/TiO₂/Si₃N₄ nanocomposites have been prepared from PVP as polymer matrix with TiO₂/Si₃N₄ NPs as filler. The nanocomposites films of PVP/TiO₂/Si₃N₄ nanomaterials were fabricated using casting technique. The films prepared with different concentrations: $C_1 = 12.5$ gm/L, $C_2 = 25$ gm/L, and $C_3 = 50$ gm/L and ratio of TiO₂/Si₃N₄ NPs (6%) provided with concentration of 50% TiO₂ and 50% Si₃N₄.

The dielectric properties of PVP/TiO₂/Si₃N₄ nanocomposites were examined at frequency (F) ranged from 100 Hz to 5 MHz using LCR meter (HIOKI 3532-50 LCR HI TESTER).

The dielectric constant (ϵ') is given by [48]:

$$\epsilon' = C_p / C_0, \quad (1)$$

wherever C_p is the capacitance of matter and C_0 is the vacuum capacitance.

Dielectric loss (ϵ'') is determined by [49]:

$$\epsilon'' = \epsilon' D, \quad (2)$$

where D is the dispersion factor.

The A.C. electrical conductivity is obtained by [50]:

$$\sigma_{A.C.} = 2\pi F \epsilon' D \epsilon_0. \quad (3)$$

3. RESULTS AND DISCUSSION

Figures 1 and 2 show the variation of dielectric constant with frequency and concentration for PVP/TiO₂/Si₃N₄ nanocomposites, respectively.

Because the values of dielectric constant drop with increasing frequency, for the dipole, it is difficult to spin accurately and easily, and its oscillation begins to occur after this field. This is because the dielectric-constant values decrease.

In addition, there was no evidence of relaxation peaks, which points to a non-Debye response.

Figures 3 and 4 demonstrates the dielectric loss behaviours with frequency and concentration, respectively, which show that the mo-

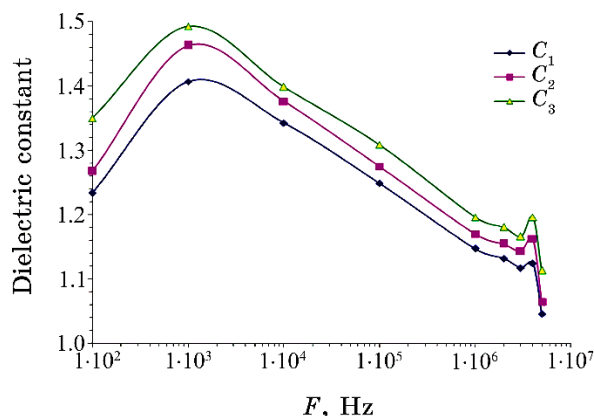


Fig. 1. Variation of dielectric constant for PVP/TiO₂/Si₃N₄ nanocomposites with frequency.

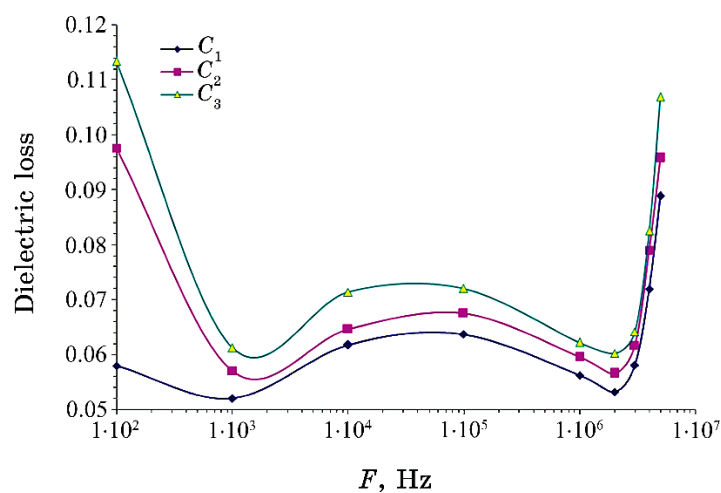


Fig. 2. Dielectric loss variation for PVP/TiO₂/Si₃N₄ nanocomposites with frequency.

tion of ions is recognized as the fundamental foundation of nanocomposite dielectric loss at lower frequencies, leading to a decrease in dielectric loss as a function of rising frequency.

Thus, the high value of the dielectric loss at low frequencies indicates the impact of ion jumping. The dielectric constant and dielectric loss are increased with increasing concentration that is attributed to rise in the number of charge carriers [51–63].

The performances of A.C. electrical conductivity of PVP/TiO₂/Si₃N₄ nanocomposites with frequency and concentration are represented in

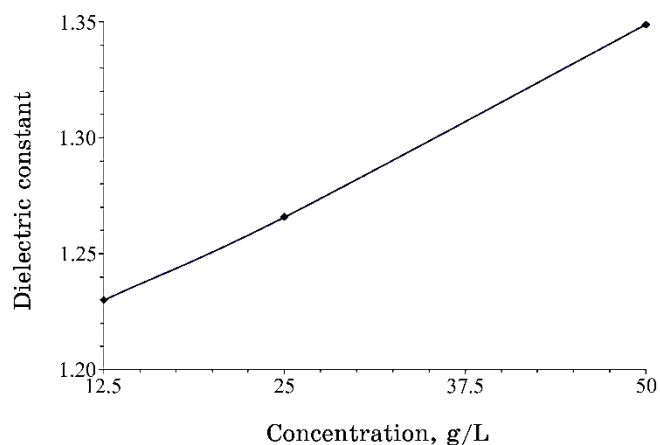


Fig. 3. Behaviour of dielectric constant for PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites with concentration.

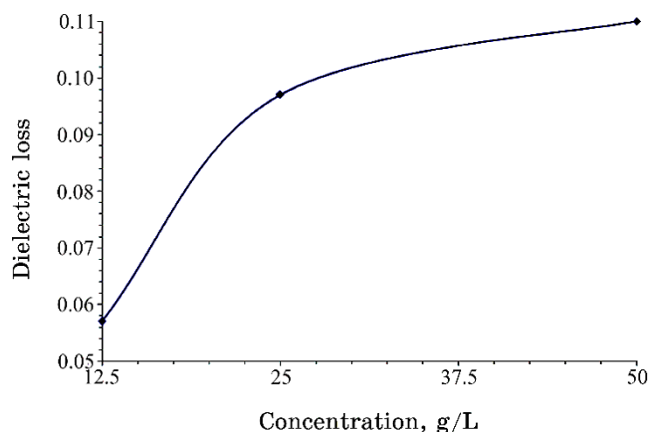


Fig. 4. Dielectric loss performance for PVP/ $\text{TiO}_2/\text{Si}_3\text{N}_4$ nanocomposites with concentration.

Figs. 5 and 6, respectively.

The A.C. conductivity increases with the concentration.

In all films, conductivity increases with frequency. The bonds are designed to switch at higher frequencies, resulting in a dielectric transition with vulnerable trustworthy polar functional groups, which causes physiological adaptations within the polymer structure *via* the formation of charge transfer complexes, implying increased electrical conductivity of the films.

The rise of A.C. electrical conductivity with concentration can be due to increase of charge-carriers' number [64–70].

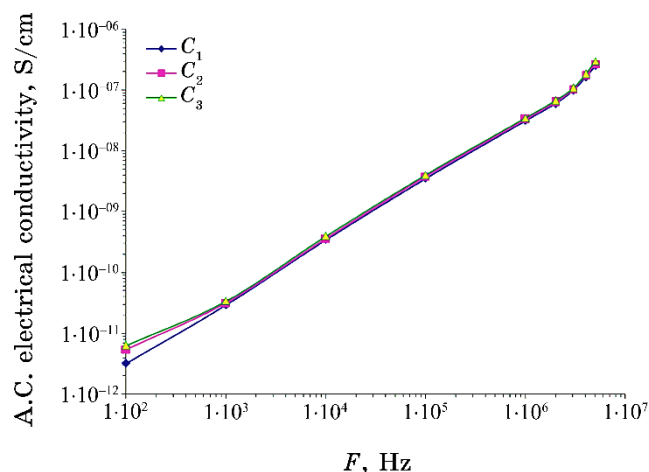


Fig. 5. Performance of A.C. electrical conductivity for PVP/TiO₂/Si₃N₄ nanocomposites with frequency.

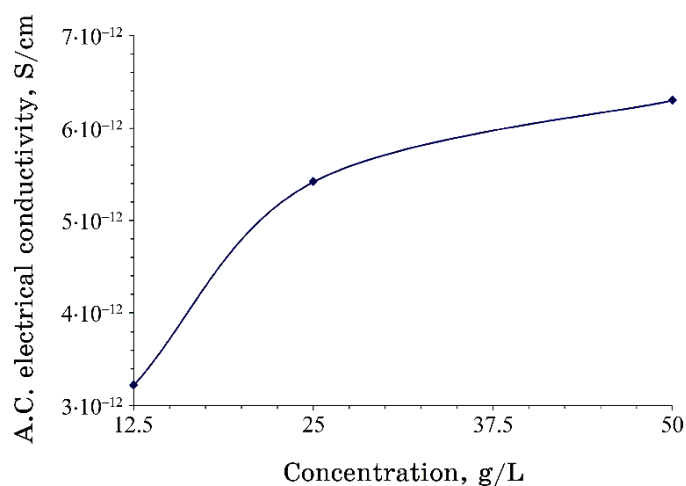


Fig. 6. Behaviour of A.C. electrical conductivity for PVP/TiO₂/Si₃N₄ nanocomposites with concentration.

4. CONCLUSIONS

The present study includes an investigation of A.C. electrical properties for PVP/TiO₂/Si₃N₄ nanocomposites to utilize them in different electrical and electronics fields. The A.C. electrical properties of PVP/TiO₂/Si₃N₄ nanocomposites were tested in frequency ranged of 100 Hz–5 MHz.

The results demonstrated that the dielectric constant, dielectric loss and electrical conductivity are increased with an increase in concentration. The dielectric constant and dielectric loss of PVP/TiO₂/Si₃N₄ nanocomposites are reduced, while the electrical conductivity is increased, with increasing of the frequency. The final results designated that the PVP/TiO₂/Si₃N₄ nanocomposites can be functional in many electrical and electronics applications.

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